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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/075,656	02/13/2002	Detlev Richter	P2001,0097	9370
24131	7590	01/11/2007	EXAMINER	
LERNER GREENBERG STEMER LLP			TABONE JR, JOHN J	
P O BOX 2480			ART UNIT	PAPER NUMBER
HOLLYWOOD, FL 33022-2480			2138	
SHORTENED STATUTORY PERIOD OF RESPONSE		MAIL DATE	DELIVERY MODE	
3 MONTHS		01/11/2007	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

Office Action Summary	Application No.	Applicant(s)
	10/075,656	RICHTER, DETLEV
	Examiner	Art Unit
	John J. Tabone, Jr.	2138

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) Responsive to communication(s) filed on 06 October 2006.
- 2a) This action is FINAL. 2b) This action is non-final.
- 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) Claim(s) 1-13 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) Claim(s) _____ is/are allowed.
- 6) Claim(s) 1-13 is/are rejected.
- 7) Claim(s) _____ is/are objected to.
- 8) Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) The specification is objected to by the Examiner.
- 10) The drawing(s) filed on 02 November 2004 is/are: a) accepted or b) objected to by the Examiner. Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a). Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) All b) Some * c) None of:
 1. Certified copies of the priority documents have been received.
 2. Certified copies of the priority documents have been received in Application No. _____.
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) Notice of References Cited (PTO-892)
- 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) Information Disclosure Statement(s) (PTO/SB/08)
Paper No(s)/Mail Date _____.
- 4) Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____.
- 5) Notice of Informal Patent Application
- 6) Other: _____.

DETAILED ACTION

1. Claims 1-13 remain pending in the current application and have been examined.

Response to Arguments

2. Applicant's arguments, see Appeal Brief, filed 10/06/2006, with respect to the rejection(s) of independent claim(s) 1 and 7 under 35 U.S.C. 102(e) have been fully considered and are persuasive. Therefore, the rejection has been withdrawn. However, upon further consideration, a new ground(s) of rejection is made.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claim 1-5, 7-10, 12 and 13 are rejected under 35 U.S.C. 103(a) as being unpatentable over Bates et al. (US-6477674), hereinafter Bates.

Claims 1, 3-5, 7 and 9:

Bates teaches an integrated circuit (IC) 500 which includes input/output (I/O) buffers 100(1)-100(n) in a block diagram shown in FIG. 5 (**bidirectionally operating interface circuits**). Bates also teaches I/O buffers 100(1)-100(n) make up a data block

of I/O circuitry for transmitting to and receiving data from other IC 100 devices (**first and second equally sized groups of interface circuits**). (Col. 4, ll. 28-32). Bates further teaches test pattern generator 210 is coupled to MUX 205 and MUX 115, and is used to generate test pattern signals for testing I/O test circuit 100 upon the initiation of a loopback test (**a first circuit...serving to generate test signals...**). Bates discloses test pattern generator 210 may be implemented with two or more flip flops, **a linear feedback register** (also as per claim 4), **a random pattern generator** (also as per claims 3 and 9) or random access memory (RAM). Bates suggests the test pattern signals may be loaded into test pattern generator 210 from an integrated circuit tester (not shown) via a test chain prior to conducting a loopback test (**a respective electrical connection... outside of the semiconductor module for enabling a self-test**). Bates teaches compare unit 220 compares test signals received from stage unit 215 with test signals received from amp 145, after having passed through the components of I/O buffer 100 (**a second circuit... for receiving and process test signals...**). Bates also teaches if compare unit 220 detects a difference between the signals received from amp 145 and those received from test pattern generator 210, an error signal is transmitted from compare unit 220 (**a second circuit... for receiving and process test signals..., also calculating a signature... and comparing ... with a prescribed signature** as per claims 5 and 9). Bates also teaches the compare unit 220 may be implemented using an Exclusive-Or-Gate or other comparison logic may be used to implement compare unit 220. (Col. 3, l. 46 through col. 4, l. 13). Bates further teaches V_{REF} pad

140 receives an external reference voltage (a **respective separate voltage supply...**).
(Col. 2, l. 65).

Bates does not explicitly teach "first and second equally sized groups of interface circuits, wherein each interface circuit of said first group is assigned exactly one interface circuit of said second group" and "a first circuit connected to said first group and serving to generate test signals to be multiplexed in and output via said interface circuits of said first group; a second circuit connected to said second group for receiving and processing test signals received via said interface circuits of said second group".

However, Bates does teach I/O buffers 100(1)-100(n) make up a data block of I/O circuitry for transmitting to and receiving data from other IC 100 devices (**first and second equally sized groups of interface circuits**). (Col. 4, ll. 28-32). In Figure 5, which is a block diagram of one embodiment of an integrated circuit (IC) 500 that includes input/output (I/O) buffers 100(1)-100(n). I/O buffers 100(1)-100(n) make up a data block of I/O circuitry for **transmitting to and receiving data from other IC 100 devices**. Bates continues to teach that a data block includes sixteen (16) I/O buffers 100. However, in other embodiments, a data block may include other multiples (e.g., 2, 4, 8, 12, 18, 32, 40, 64, etc.) of I/O buffers 100. (Col. 4, ll. 28-37).

It would have been obvious to one of ordinary skill in the art at the time the invention was made that the "other IC 100 devices" Bates is referring to, as interpreted by the Examiner, is a duplication of IC 500 that includes other groups of input/output (I/O) buffers 100(1)-100(n), which qualifies the "other IC 100 devices" as the second group. The artisan would be motivated to do so because the I/O buffers 100 (i.e. as well

as other IC 100 devices) are groups that are duplicated and therefore, comprises the same number of input/output buffers as the first group.

Claim 2:

**“a third circuit connected to said and serving to generate test signals
interface circuits of be multiplexed in and output via said second group”**

Bates teaches MUX 225 is coupled to compare unit 220 and latch 230. MUX 225 selects signals from compare unit 220 whenever a loopback test is in progress at I/O buffer 110, and selects the scan chain path after the test pattern is complete.

**“wherein said second circuit connected to said first group for receiving
and processing test signals received via said interface circuits of said first
group”**

Bates teaches compare unit 220 compares test signals received from stage unit 215 with test signals received from amp 145, after having passed through the components of I/O buffer 100. Bates also teaches if compare unit 220 detects a difference between the signals received from amp 145 and those received from test pattern generator 210, an error signal is transmitted from compare unit 220. (Col. 3, l. 66 through col. 4, l. 13).

Claim 8:

**“after processing the test signals output by the first group and received by
the second group of interface circuits, reversing a test direction...”**

Bates teaches I/O buffers 100(1) and 100(n) support AC I/O loopback testing. Bates also teaches although I/O buffer 100 may be determined to be functional after a

standard I/O loopback test, an AC loopback test provides the capability of detecting more subtle defects in the components of I/O buffer 100 that may effect timing. Thus, conducting an AC I/O loopback test examines the AC I/O loopback of the input and output paths of I/O buffer 100(x) (reversing a test direction).

Claim 10:

“influencing a connection of the assigned interface circuits in order to include an influence of interference quantities in the self-test”.

Bates suggests the test pattern signals may be loaded into test pattern generator 210 from an integrated circuit tester (not shown) via a test chain prior to conducting a loopback test.

Claim 12 and 13:

“modulating low-frequency signal voltages onto at least one of the supply voltages of the interface groups” as per claim 12.

“modulating two low-frequency sinusoidal signals of different frequency onto both supply voltages” as per claim 13.

Bates teaches V_{REF} pad 140 receives an external reference voltage, differential amplifier (amp) 145 is coupled to I/O pad 135 and V_{REF} pad 140 and amp 145 aggregates signals received from I/O pad 135 and V_{REF} pad 140 into a single signal. Bates also teaches amp 145 transmits a logical one whenever a signal received at I/O pad 135 is higher in magnitude than a signal received at V_{REF} pad 140. Bates further teaches amp 145 transmits a logical zero whenever a signal received at I/O pad 135 is

lower in magnitude than a signal received at V_{REF} pad 140. However, it is understood by one of ordinary skill in the art that the operation of amp 145 may be reversed.

4. Claim 6 is rejected under 35 U.S.C. 103(a) as being unpatentable over Bates et al. (US-6477674), hereinafter Bates, in view of Takagi (US-6704897), hereinafter Takagi.

Claim 6:

Bates does not explicitly teach a multiple input shift register (MISR) for receiving and processing test signals. However, Bates does teach compare unit 220 may be implemented using an Exclusive-Or-Gate or other comparison logic. It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Bates' compare unit 220 with Takagi compaction circuit 13 (MISR). The artisan would have been motivated to do so because this would enable Bates' compare unit 220 to further evaluate consecutively store the resulting random data Takagi's flip flop 70'.

5. Claim 11 is rejected under 35 U.S.C. 103(a) as being unpatentable over Bates et al. (US-6477674), hereinafter Bates, in view of Levy et al. (US-5751151), hereinafter Levy.

Claim 11:

Bates does not explicitly teach of the influencing step consisting of resistive, capacitive and inductive. However, Levy suggests when VDD potential is to be applied to the corresponding pin of the DUT 10A and 10B, a corresponding relay coil, such as

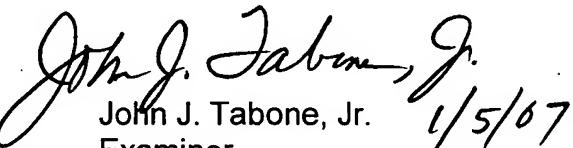
the relay coil 30 (inductive influence), is operated to pull the contact 26 from its lower position to its upper position, where it then is attached to a source or operating potential (VDD) as illustrated in FIG. 1. (Col. 4, lines 28-33). It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Bates' testing method to include Levy's method of applying VDD influences via the corresponding relay coils. The artisan would have been motivated to do so because this would give Bates more flexibility in applying power sources to the DDR I/O interface circuits during testing.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John J. Tabone, Jr. whose telephone number is (571) 272-3827. The examiner can normally be reached on M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Albert DeCady can be reached on (571) 272-3819. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system; see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.


John J. Tabone, Jr.
Examiner
Art Unit 2138
1/5/07


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